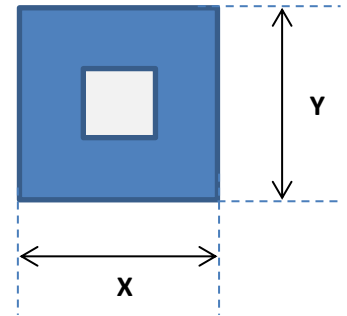




X-Ray Microscopy Windows Specification Sheet

Frame:

	Unit	Description
Material	-	Silicon (Si)
Thickness	μm	100, 200
Thickness tolerance	%	5
Resistivity	$\Omega\text{-cm}$	1-30
Dimension X	mm	5, 7.5, 10
Dimension Y	mm	5, 7.5, 10
Window (Square)	mm^2	0.05x0.05 to 5x5



Membrane:

	Unit	Description
Material	-	Low stress LPCVD Silicon Nitride
Thicknesses available	nm	10 to 2000
Thickness tolerance	%	≤ 5
Film stress	MPa	≤ 250
Dielectric constant	-	6-7
Dielectric strength	10^6 V/cm	10
Resistivity	$\Omega\text{-cm}$	10^{16}
Young's modulus	GPa	270
Density	g/cm^3	3.1
Roughness (Ra)	nm	$0.36 \pm 5\%$
Roughness (rms)	nm	$0.46 \pm 5\%$
Radius of Curvature	m	> 400
Refractive index @ 630nm	-	2.15-2.17

